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Chan et al.

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(54) **ELECTRON MICROSCOPE**

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(**) Term: **14 Years**

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(51) **LOC (9) Cl.** **16-06**

(52) **U.S. Cl.** **D16/131**

(58) **Field of Classification Search** D16/130, D16/131; 359/385, 368, 399, 802, 803, 806, 359/808, 809, 810, 817, 379; 362/202, 205; D26/37; D8/107, 83
See application file for complete search history.

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(57) **CLAIM**

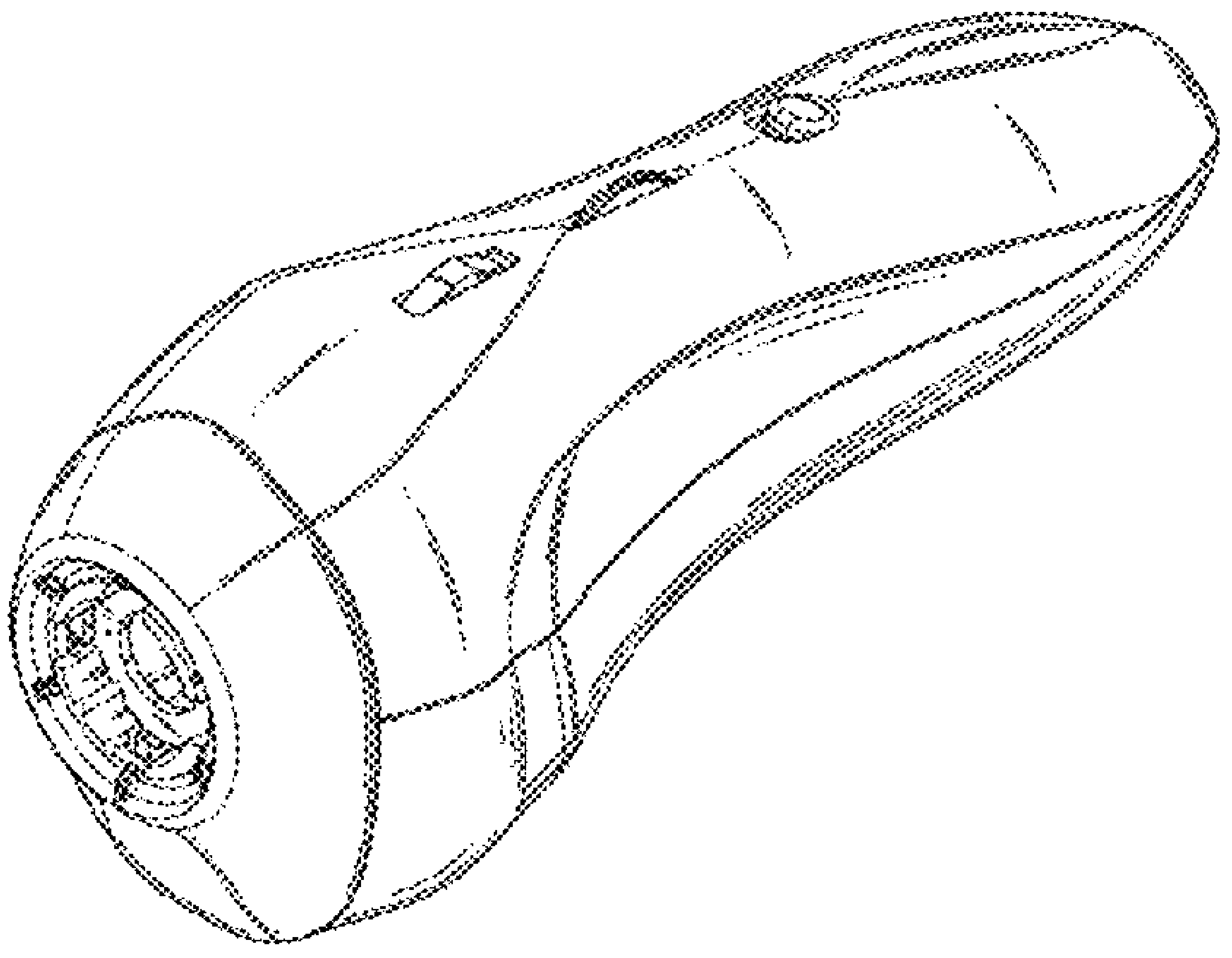
The ornamental design for an electron microscope, as shown and described.

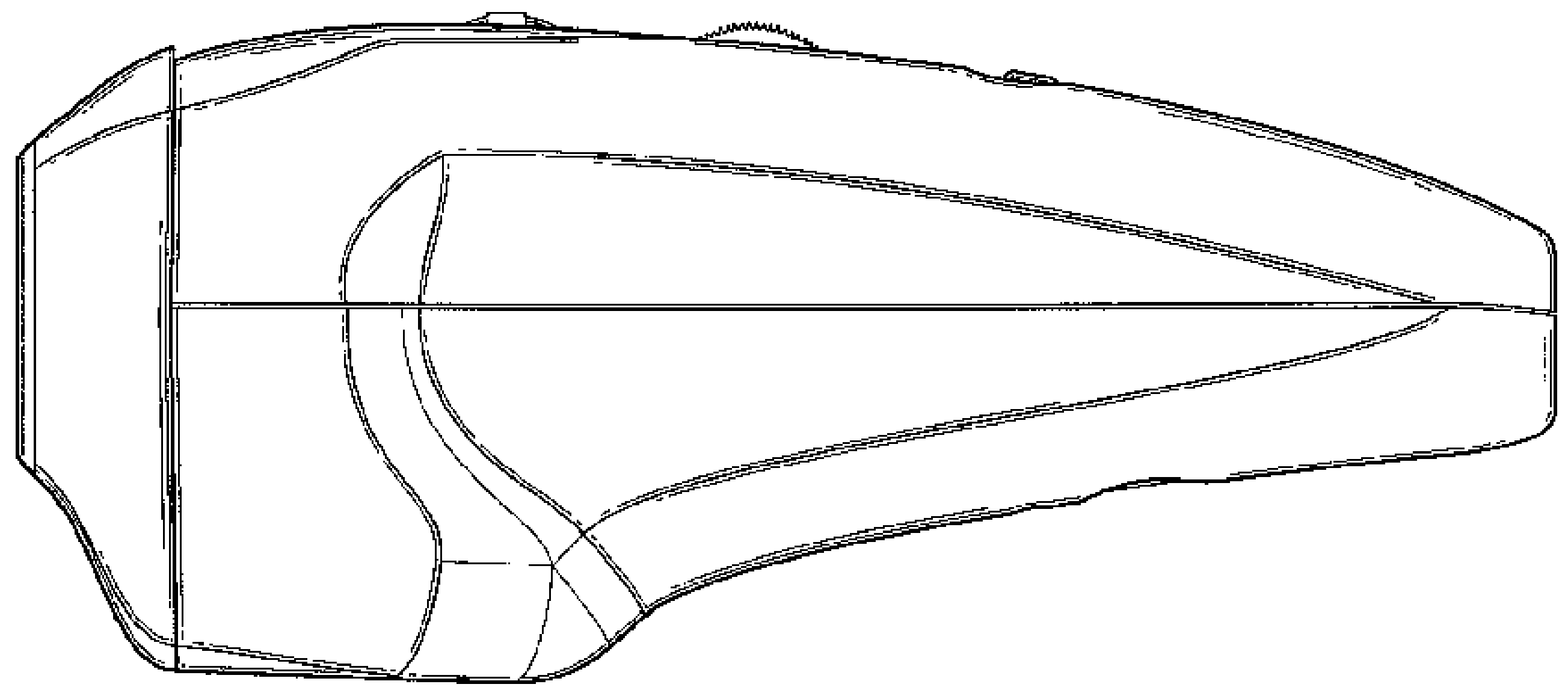
DESCRIPTION

FIG. **1** is a perspective view of the electron microscope showing our new design;
FIG. **2** is a front elevation view thereof;
FIG. **3** is a rear elevation view thereof;
FIG. **4** is a left side view thereof;
FIG. **5** is a right side view thereof;
FIG. **6** is a top elevation view thereof; and,
FIG. **7** is a bottom perspective view.

The broken lines illustrate portions of the electron microscope that form no part of the claimed design.

1 Claim, 4 Drawing Sheets





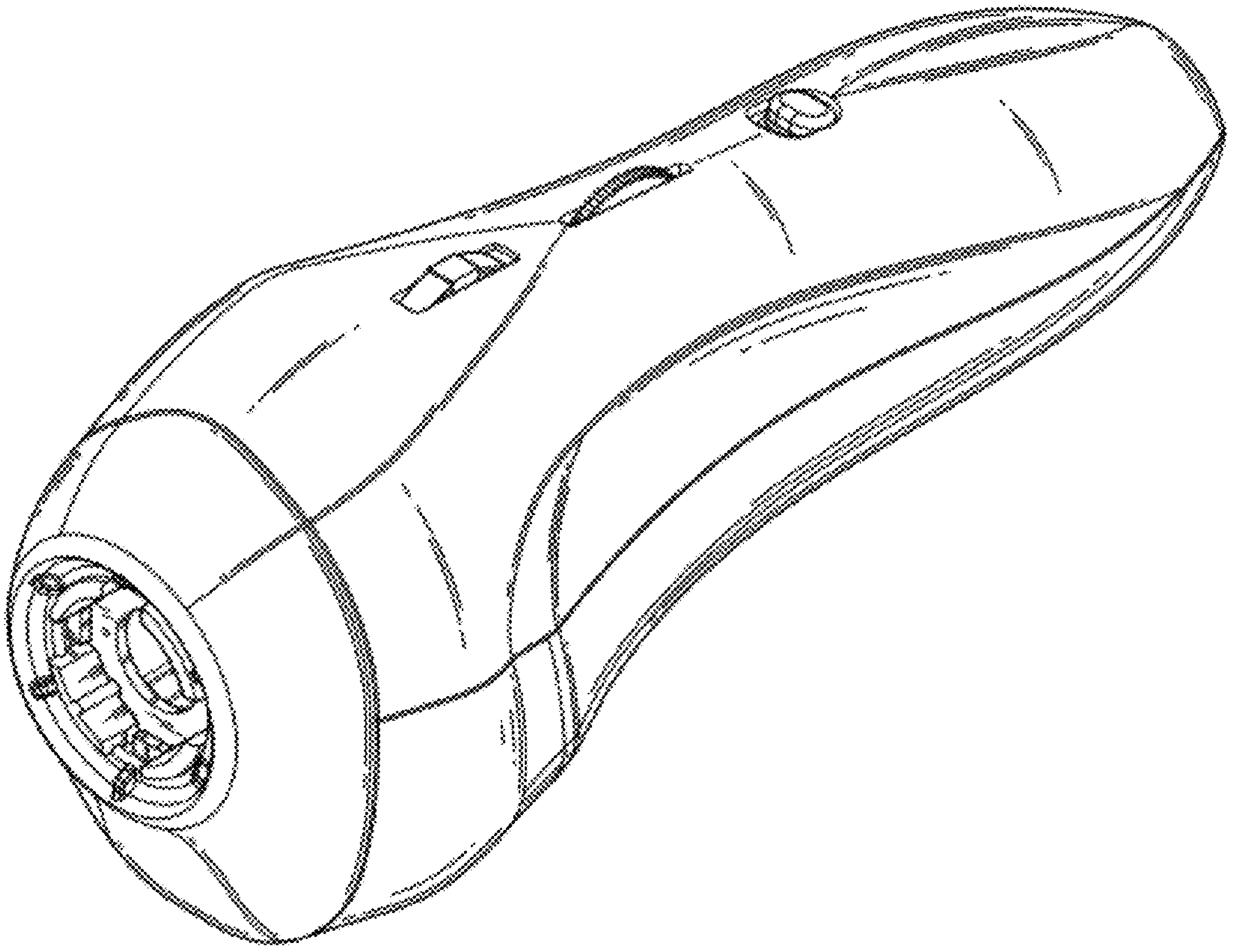


Fig .1

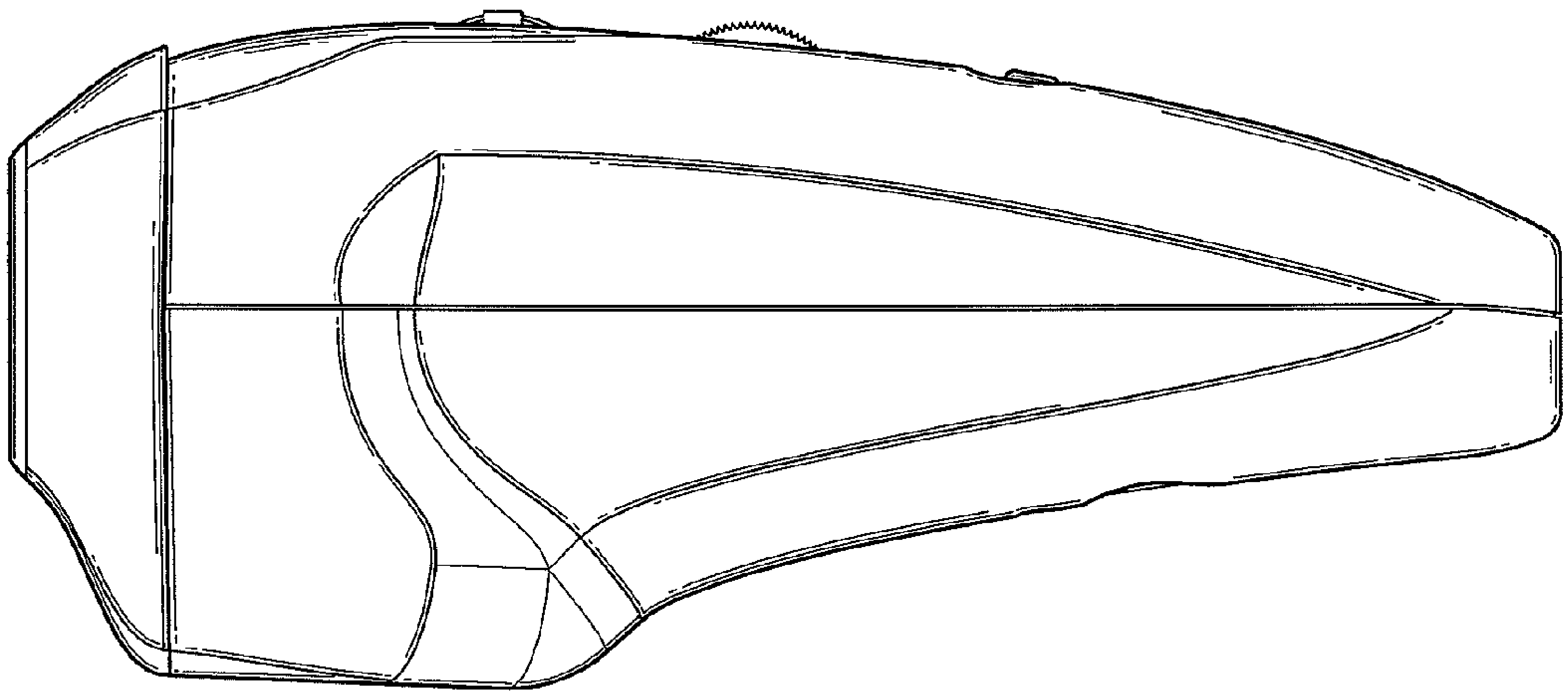


Fig .2

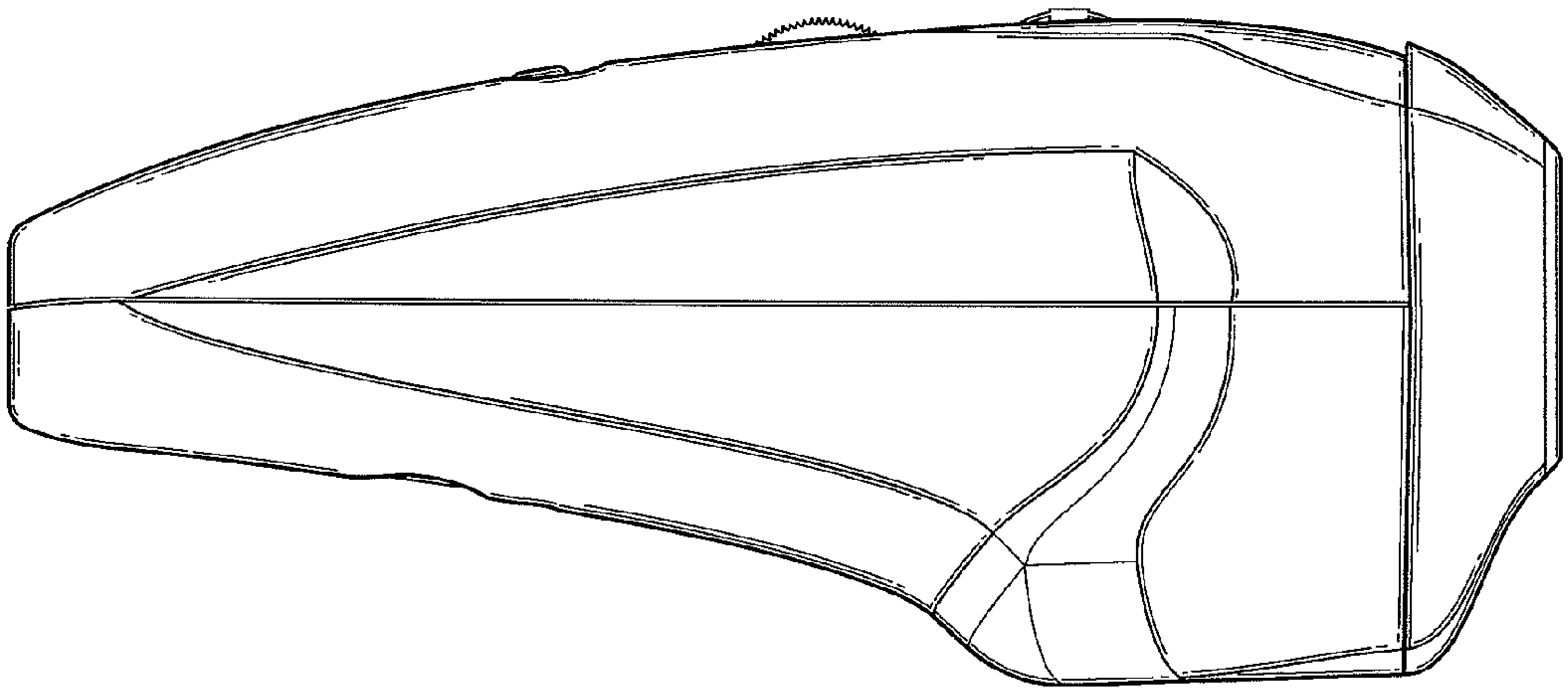


Fig .3

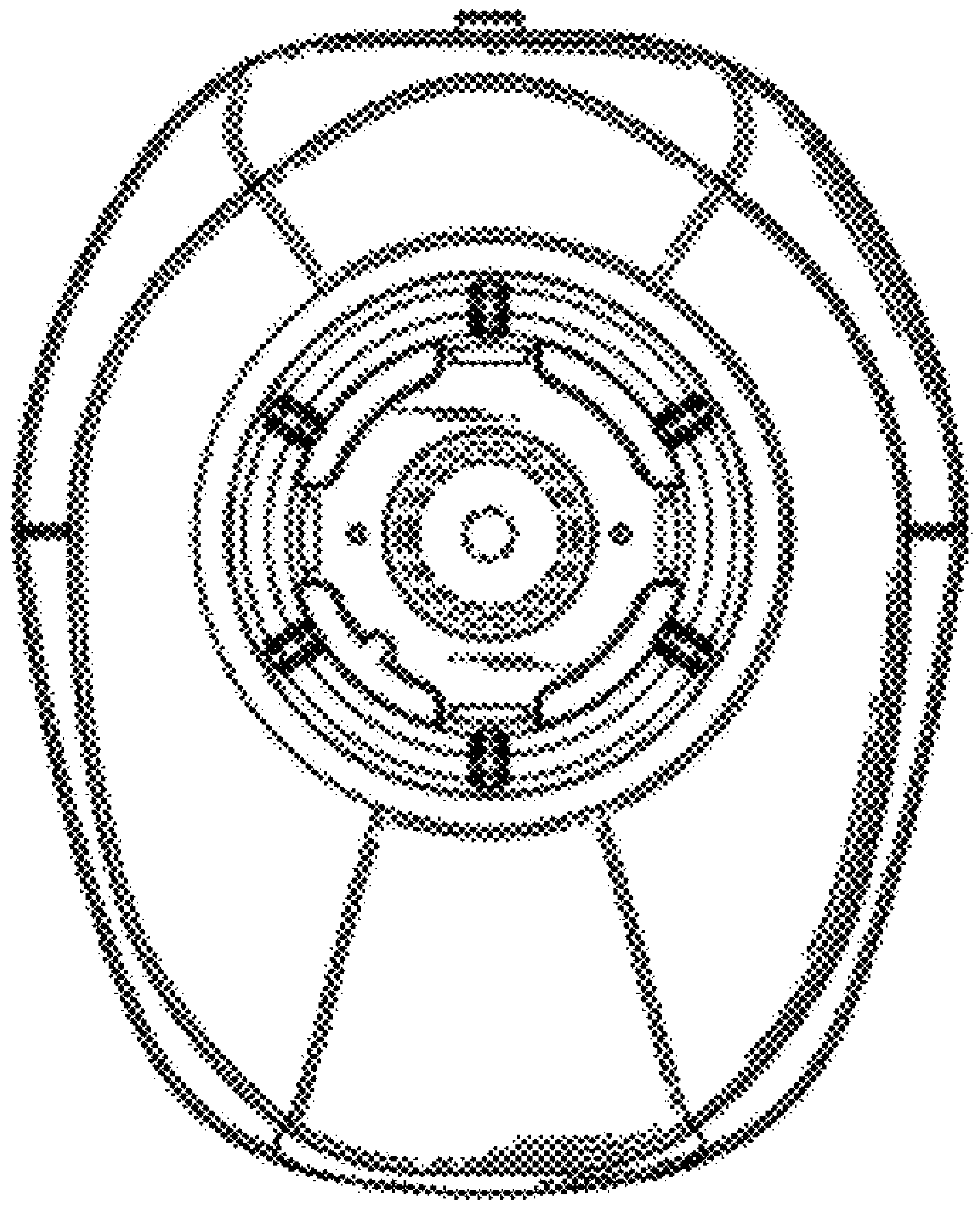


Fig . 4

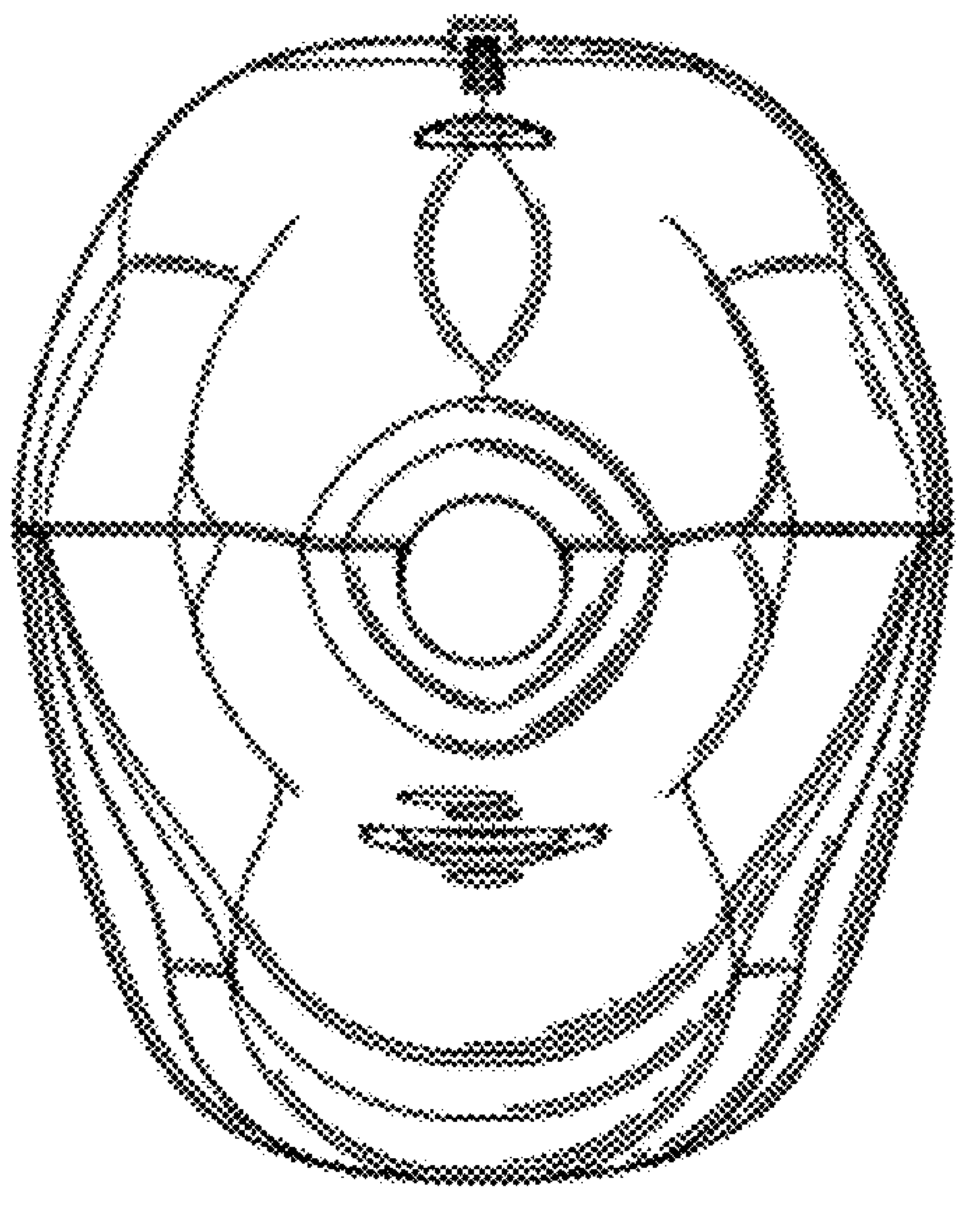


Fig . 5

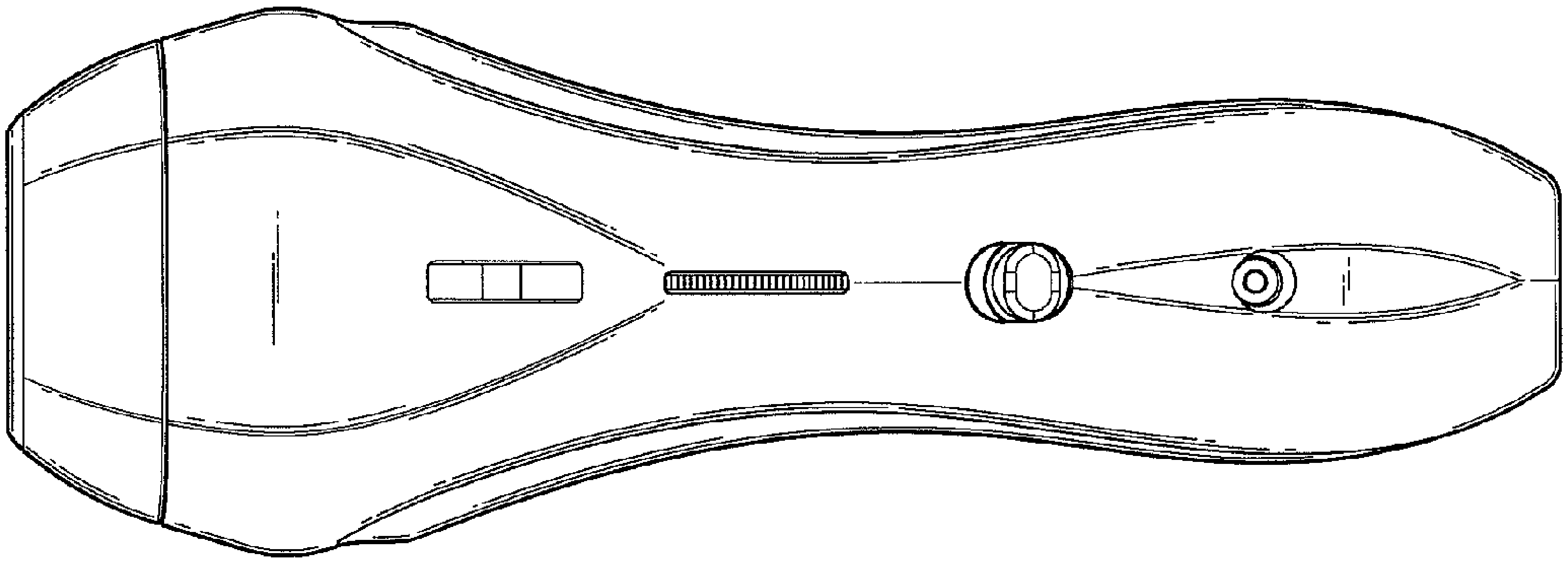


Fig .6

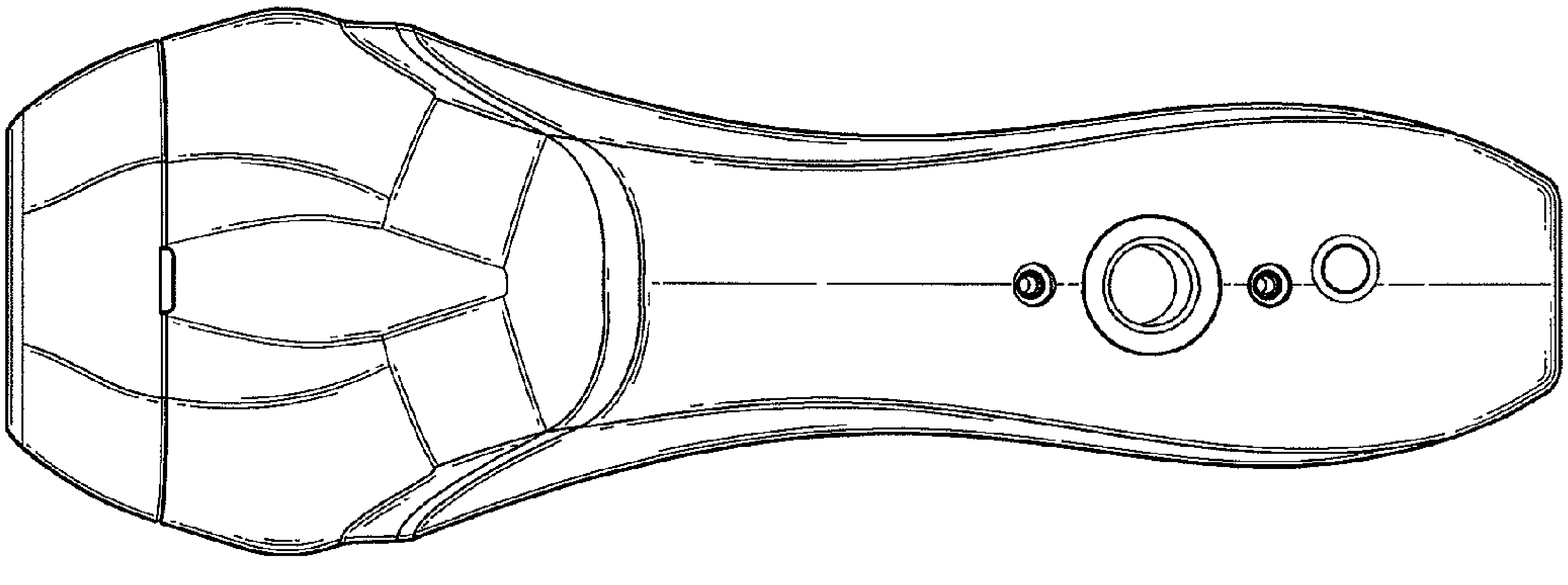


Fig .7